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APPLICATION NO.		FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/660,477		09/12/2003	Richard A. Haight	20140-00303-US1	6311	
30678	7590	06/15/2006		EXAM	EXAMINER	
CONNOL	LY BOV	'E LODGE & HUT2	EVANS, GE	EVANS, GEOFFREY S		
	SUITE 800 1990 M STREET NW				PAPER NUMBER	
WASHING	WASHINGTON, DC 20036-3425					
				DATE MAILED: 06/15/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

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		Application No.	Applicant(s)					
		10/660,477	HAIGHT ET AL.					
	Office Action Summary	Examiner	Art Unit					
		Geoffrey S. Evans	1725					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply								
WHIC - Exter after - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR REPLY CHEVER IS LONGER, FROM THE MAILING DAMPS of 37 CFR 1.11 SIX (6) MONTHS from the mailing date of this communication. Depriod for reply is specified above, the maximum statutory period were to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	N. nely filed the mailing date of this communication D (35 U.S.C. § 133).					
Status								
1)🛛	Responsive to communication(s) filed on 27 M	arch 2006.						
2a) <u></u> ☐	This action is FINAL . 2b) This action is non-final.							
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
	closed in accordance with the practice under E	x parte Quayle, 1935 C.D. 11, 45	i3 O.G. 213.					
Dispositi	ion of Claims							
5)⊠ 6)⊠ 7)□	Claim(s) 1-42 and 44-52 is/are pending in the at 4a) Of the above claim(s) is/are withdraw Claim(s) 1-37 and 40-42 is/are allowed. Claim(s) 38,39,44-52 is/are rejected. Claim(s) is/are objected to. Claim(s) are subject to restriction and/or	vn from consideration.						
Applicati	on Papers							
10)	The specification is objected to by the Examine The drawing(s) filed on is/are: a) access applicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Ex	epted or b) objected to by the Idrawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121	(d).				
Priority u	ınder 35 U.S.C. § 119							
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 								
Attachmen	t(s) e of References Cited (PTO-892)	d\ □ Intonion Summer	(PTO 412)					
2) Notic 3) Inform	e of References Cited (PTO-692) e of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449 or PTO/SB/08) r No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:						

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DETAILED ACTION

1. The indicated allowability of the subject matter of claims 44-46 in the last office action is withdrawn in view of the prior art references subsequently discovered.

- 2. Claims 38-39 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention. Claims 38 and 39 depend upon claims 1,9 (indirectly through claim 15),16 and 23. Claims 1,9,16 and 23 all recite that the laser pulses are extreme ultraviolet or EUV. The instant specification discloses (see paragraph 44) that 157 nm is merely deep ultraviolet (DUV) and not extreme ultraviolet (EUV). Therefore claims 38 and 39 contradict and confusingly broaden the subject matter in claims 1,9,16 and 23.
- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 44,47,48 are rejected under 35 U.S.C. 103(a) as being unpatentable over Zait in U.S. Patent Application Publication No. 2005/0084767 in view of Cheng et al. in U.S. Patent Application Publication No. 2002/0172235 A1 and Miyazaki et al. in the article "High-Order Harmonic Generation in the Soft X-ray to XUV by ultrashort Laser Pulses". Zait et al. discloses an apparatus for repairing a defect on a photomask comprising a laser (element 1) capable of providing a femtosecond pulse width laser

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light (see paragraph 74), a harmonics generator (see paragraph 75), an objective lens (see paragraph 78), and a control unit (variable attenuator 3, see paragraph 75). Zait et al. does not disclose that the harmonics generator is a harmonic conversion cell, nor does Zait et al. disclose using a filter. Miyazaki et al. teaches using a harmonic conversion cell with a rare gas to allow tuning of the wavelength as low as 7.6 nm, so Miyazaki is capable of tuning to 13 nm. Cheng et al. further teaches using a filter (see figure 7) to filter out undesired wavelengths. It would have been obvious to adapt Zait et al. in view of Cheng et al. and Mayazaki et al. to provide this to permit tuning of the wavelength to the material in the mask to increase ablation efficiency.

5. Claims 45,49, and 50 are rejected under 35 U.S.C. 103(a) as being unpatentable over Zait in U.S. Patent Application Publication No. 2005/0084767 in view of Cheng et al. in U.S. Patent Application Publication No. 2002/0172235 A1, and Yamada et al. in U.S. Patent No. 2003/0213770 A1. Zait et al. (767) disclose an apparatus for repairing a defect on a photomask comprising a laser (element 1) capable of providing a femtosecond pulse width laser light (see paragraph 74), a harmonics generator (see paragraph 75), an objective lens (see paragraph 78), and a control unit (variable attenuator 3, see paragraph 75). Zait et al. (767) does not disclose that the harmonics generator is a harmonic conversion cell, nor does Zait et al. (767) disclose using a filter. Chang et al. teaches using a harmonic conversion cell with a rare gas to allow tuning of the wavelength (e.g. see paragraph 32), Cheng et al. further teaches using a filter (see figure 7) to filter out undesired wavelengths. Yamada et al. teaches that it is known to use a 157 nm for laser processing (see paragraph 10) and using a laser with an output

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of 800nm (see paragraph 94). It would have been obvious to adapt Zait et al. in view of Cheng et al., and Yamada et al. to provide this to be able to select the harmonic permit tuning of the wavelength to 157 nm to achieve the same characteristics as the fundamental wavelength of the F₂ excimer laser while having ultrashort laser pulses to prevent undesired thermal effects.

Claims 46,51, and 52 are rejected under 35 U.S.C. 103(a) as being unpatentable 6. over Zait in U.S. Patent Application Publication No. 2005/0084767 in view of Cheng et al. in U.S. Patent Application Publication No. 2002/0172235 A1 and Zait et al. in U.S. 2002/0086245 A1. Zait et al. (767) discloses an apparatus for repairing a defect on a photomask comprising a laser (element 1) capable of providing a femtosecond pulse width laser light (see paragraph 74), a harmonics generator (see paragraph 75), an objective lens (see paragraph 78), and a control unit (variable attenuator 3, see paragraph 75). Zait et al. (767) does not disclose that the harmonics generator is a harmonic conversion cell, nor does Zait et al.(767) disclose using a filter. Chang et al. teaches using a harmonic conversion cell with a rare gas to allow tuning of the wavelength (e.g. see paragraph 32), Cheng et al. further teaches using a filter (see figure 7) to filter out undesired wavelengths. Zait et al. (245) teaches using ultrashort laser pulses (femtoseconds, see paragraph 31) and using the ArF laser which has a first harmonic wavelength of 193 nm wavelength (see paragraph 100) to manufacture a reticle (mask). It would have been obvious to adapt Zait et al.(767) in view of Cheng et al. and Zait et al. (245) to provide this to permit tuning of the wavelength to the material in the mask to increase ablation efficiency.

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7. Applicant's arguments with respect to claims of record have been considered but

are moot in view of the new ground(s) of rejection.

8. Claims 1-37,40-42 are allowed.

9. Claims 38 and 39 would be allowable if rewritten or amended to overcome the

rejection(s) under 35 U.S.C. 112, 2nd paragraph, set forth in this Office action.

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Geoffrey S Evans whose telephone number is (571)-

272-1174. The examiner can normally be reached on Mon-Fri 6:30AM to 4:00 PM,

alternate Fridays off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Pat Ryan can be reached on (571)-272-1292. The fax phone number for

the organization where this application or proceeding is assigned is (571)-273-8300.

GSE

Geφ**f**frey S. Evans
Primary Examiner

Group 1700